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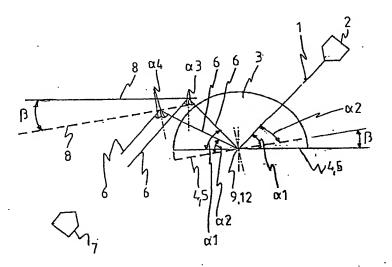
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(54) Title: METHOD AND DEVICE FOR CARRYING OUT SURFACE PLASMON RESONANCE MEASUREMENT



(57) Abstract: The invention relates to a method and a device for carrying out surface plasmon resonance measurement. A beam (1) of electromagnetic radiation is produced by a source (2) of electromagnetic radiation. Said beam (1) of electromagnetic radiation is directed through a prism (3) onto a material layer (5) in an angle (a1; a2) of incidence, which material layer (5) covers a planar surface (4) of the prism (3). A resonance phenomenon is caused. A beam (6) of reflected electromagnetic radiation is produced and directed by the surface (4) to a detector (7) for detecting the level of intensity of the beam (6) of reflected electromagnetic radiation. The change of intensity of the beam (6) of reflected electromagnetic radiation, caused by the surface resonance phenomenon, is measured. Said beam (6) of reflected electromagnetic radiation is reflected with a mirror (8) to the detector (7).